**Product data sheet** 

## 1. General description

Planar passivated high commutation three quadrant triac in a SOT78 (TO-220AB) plastic package intended for use in circuits where high static and dynamic dV/dt and high dl/dt can occur. This "series CT" triac will commutate the full RMS current at the maximum rated junction temperature  $(T_{j(max)} = 150 \, ^{\circ}\text{C})$  without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

### 2. Features and benefits

- 3Q technology for improved noise immunity
- · High commutation capability with maximum false trigger immunity
- · High immunity to false turn-on by dV/dt
- High junction operating temperature capability
- High voltage capability
- · Less sensitive gate for high noise immunity
- · Planar passivated for voltage ruggedness and reliability
- · Triggering in three quadrants only

## 3. Applications

- Applications subject to high temperature
- Heating controls
- · High power motor control
- High power switching

### 4. Quick reference data

Table 1. Quick reference data

| Symbol   | Parameter                                | Conditions   | Min | Тур | Max | Unit |
|--|--|--|-----|-----|-----|------|
| $V_{DRM}$  | repetitive peak off-<br>state voltage    |  | -   | -   | 800 | V    |
| I <sub>T(RMS)</sub>                                | RMS on-state current                     | full sine wave; T <sub>mb</sub> ≤ 122 °C; <u>Fig. 1</u> ;<br><u>Fig. 2</u> ; <u>Fig. 3</u> | -   | -   | 20  | Α    |
| I <sub>TSM</sub> non-repetitive p<br>state current | non-repetitive peak on-<br>state current | full sine wave; $T_{j(init)}$ = 25 °C;<br>$t_p$ = 20 ms; Fig. 4; Fig. 5                    | -   | -   | 200 | Α    |
|  |  | full sine wave; $T_{j(init)}$ = 25 °C;<br>$t_p$ = 16.7 ms                                  | -   | -   | 220 | Α    |
| T <sub>j</sub>                                     | junction temperature                     |  | -   | -   | 150 | °C   |
| Static chara                                       | acteristics                              |  |     |     |     |      |
| I <sub>GT</sub>                                    | gate trigger current                     | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G+;$<br>$T_j = 25 \text{ °C; } Fig. 7$    | -   | -   | 35  | mA   |

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| Symbol                | Parameter                             | Conditions  | Min  | Тур | Max | Unit |
|-----------------------|---------------------------------------|---|------|-----|-----|------|
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$<br>$T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$ | -    | -   | 35  | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-};$<br>$T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$ | -    | -   | 35  | mA   |
| I <sub>H</sub>        | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>  | -    | -   | 40  | mA   |
| V <sub>T</sub>        | on-state voltage                      | I <sub>T</sub> = 24 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>   | -    | 1.2 | 1.5 | V    |
| Dynamic chara         | acteristics                           |   |      |     |     |      |
| dV <sub>D</sub> /dt   | rate of rise of off-state voltage     | $V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit  | 1250 | -   | -   | V/µs |
| dI <sub>com</sub> /dt | rate of change of commutating current | $V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 20 A; $dV_{com}/dt$ = 10 V/µs; gate open circuit              | 16   | -   | -   | A/ms |
|                       |                                       | $V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 20 A; $dV_{com}/dt$ = 1 V/µs; gate open circuit               | 38   | -   | -   | A/ms |

# 5. Pinning information

**Table 2. Pinning information** 

| Pin | Symbol | Description                    | Simplified outline | Graphic symbol |
|-----|--------|--------------------------------|--------------------|----------------|
| 1   | T1     | main terminal 1                | mb                 | T2             |
| 2   | T2     | main terminal 2                |                    | Sym051         |
| 3   | G      | gate                           |                    | Symoon         |
| mb  | T2     | mounting base; main terminal 2 |                    |                |
|     |        |                                | TO-220AB (SOT78)   |                |

# 6. Ordering information

**Table 3. Ordering information** 

| Type number  | Package  |  |         |  |  |  |
|--------------|----------|--|---------|--|--|--|
|              | Name     | Description  | Version |  |  |  |
| BTA420-800CT | TO-220AB | plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB | SOT78   |  |  |  |

# 7. Limiting values

#### **Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol              | Parameter                                | Conditions   | Min | Max | Unit |
|---------------------|--|--|-----|-----|------|
| $V_{DRM}$           | repetitive peak off-state voltage        |  | -   | 800 | V    |
| I <sub>T(RMS)</sub> | RMS on-state current                     | full sine wave; $T_{mb} \le 122 ^{\circ}\text{C}$ ; Fig. 1; Fig. 2; Fig. 3 | -   | 20  | А    |
| I <sub>TSM</sub>    | non-repetitive peak on-<br>state current | full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 20 ms;<br>Fig. 4; Fig. 5    | -   | 200 | А    |
|                     |  | full sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 16.7 ms     | -   | 220 | Α    |
| l <sup>2</sup> t    | I <sup>2</sup> t for fusing              | t <sub>p</sub> = 10 ms; sine-wave pulse                                    | -   | 200 | A²s  |
| dl <sub>T</sub> /dt | rate of rise of on-state current         | I <sub>G</sub> = 70 mA   | -   | 100 | A/µs |
| I <sub>GM</sub>     | peak gate current                        |  | -   | 2   | Α    |
| $P_{GM}$            | peak gate power                          |  | -   | 5   | W    |
| P <sub>G(AV)</sub>  | average gate power                       | over any 20 ms period  | -   | 0.5 | W    |
| T <sub>stg</sub>    | storage temperature                      |  | -40 | 150 | °C   |
| Tj                  | junction temperature                     |  | -   | 150 | °C   |

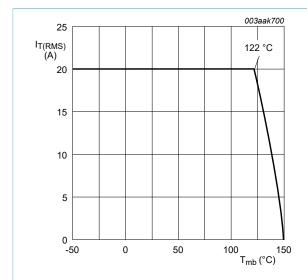


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

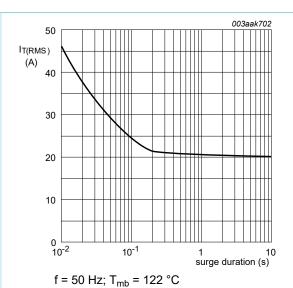


Fig. 2. RMS on-state current as a function of surge duration; maximum values

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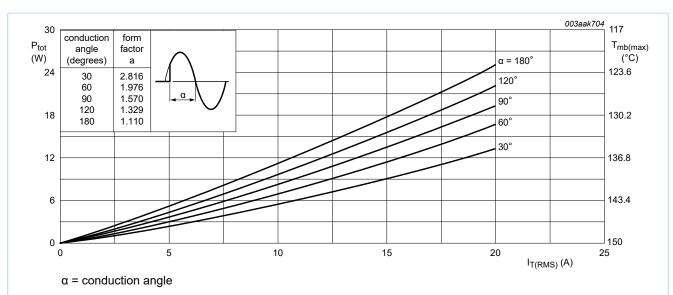


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

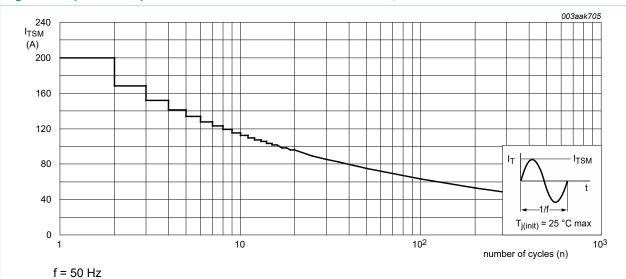
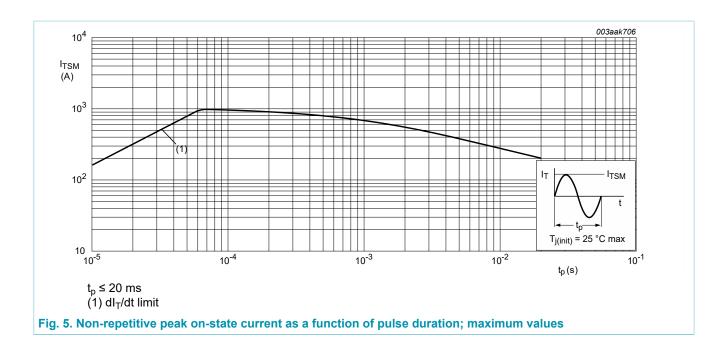


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

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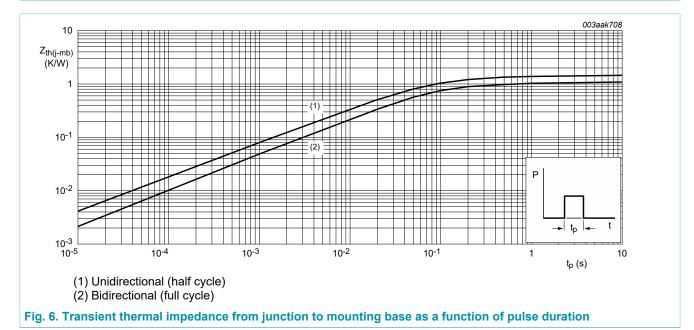
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### 8. Thermal characteristics

**Table 5. Thermal characteristics** 

| Symbol  | Parameter  | Conditions         | Min | Тур | Max | Unit |
|---|--|--------------------|-----|-----|-----|------|
| R <sub>th(j-mb)</sub> thermal resistance from junction to mounting base |  | full cycle; Fig. 6 | -   | -   | 1.1 | K/W  |
|   | _  | half cycle; Fig. 6 | -   | -   | 1.5 | K/W  |
| $R_{th(j-a)}$   | thermal resistance<br>from junction to<br>ambient free air | in free air        | -   | 60  | -   | K/W  |



## 9. Characteristics

#### **Table 6. Characteristics**

| Symbol                          | Parameter   | Conditions   | Min  | Тур | Max | Unit |
|---------------------------------|---|--|------|-----|-----|------|
| Static char                     | acteristics   |  |      |     |     |      |
| I <sub>GT</sub>                 | gate trigger current  | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } \frac{\text{Fig. 7}}{}$                           | -    | -   | 35  | mA   |
|                                 |   | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$<br>$T_j = 25 \text{ °C; } \frac{\text{Fig. 7}}{}$                                | -    | -   | 35  | mA   |
|                                 |   | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$<br>$T_j = 25 \text{ °C; } \frac{\text{Fig. 7}}{}$                                  | -    | -   | 35  | mA   |
| I <sub>L</sub> latching current | $V_D = 12 \text{ V; } I_G = 0.1 \text{ A; } T2 + G+;$<br>$T_j = 25 \text{ °C; } \frac{\text{Fig. 8}}{}$ | -  | -    | 50  | mA  |      |
|                                 |   | $V_D = 12 \text{ V; } I_G = 0.1 \text{ A; T2+ G-;}$<br>$T_j = 25 \text{ °C; } \frac{\text{Fig. 8}}{}$                                  | -    | -   | 80  | mA   |
|                                 |   | $V_D = 12 \text{ V; } I_G = 0.1 \text{ A; T2- G-;}$<br>$T_j = 25 \text{ °C; } \frac{\text{Fig. 8}}{\text{C}}$                          | -    | -   | 50  | mA   |
| l <sub>H</sub>                  | holding current   | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>   | -    | -   | 40  | mA   |
| V <sub>T</sub>                  | on-state voltage  | I <sub>T</sub> = 24 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>  | -    | 1.2 | 1.5 | V    |
| V <sub>GT</sub>                 | gate trigger voltage  | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>  | -    | 0.7 | 1   | V    |
|                                 |   | V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; <u>Fig. 11</u>  | 0.2  | 0.4 | -   | V    |
| I <sub>D</sub>                  | off-state current   | V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C  | -    | 0.2 | 1   | mA   |
| Dynamic cl                      | naracteristics  |  |      |     |     |      |
| dV <sub>D</sub> /dt             | rate of rise of off-state voltage   | $V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit                             | 1250 | -   | -   | V/µs |
| dl <sub>com</sub> /dt           | rate of change of commutating current   | $V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 20 A; $dV_{com}/dt$ = 10 V/µs; gate open circuit   | 16   | -   | -   | A/ms |
|                                 |   | $V_D = 400 \text{ V}; T_j = 150 \text{ °C}; I_{T(RMS)} = 20 \text{ A};$<br>$dV_{com}/dt = 1 \text{ V}/\mu\text{s}; gate open circuit}$ | 38   | -   | -   | A/ms |

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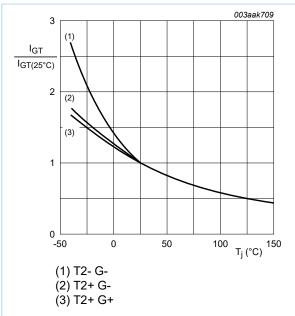


Fig. 7. Normalized gate trigger current as a function of junction temperature

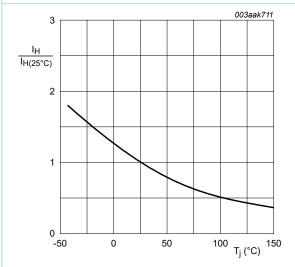


Fig. 9. Normalized holding current as a function of junction temperature

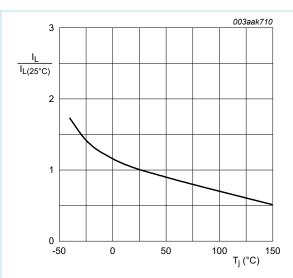
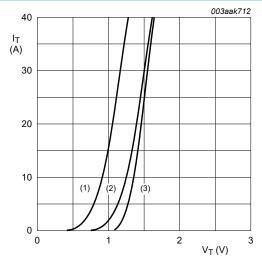


Fig. 8. Normalized latching current as a function of junction temperature



 $V_o$  = 1.087 V;  $R_s$  = 0.014  $\Omega$ 

(1)  $T_j = 150$  °C; typical values (2)  $T_j = 150$  °C; maximum values (3)  $T_j = 25$  °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

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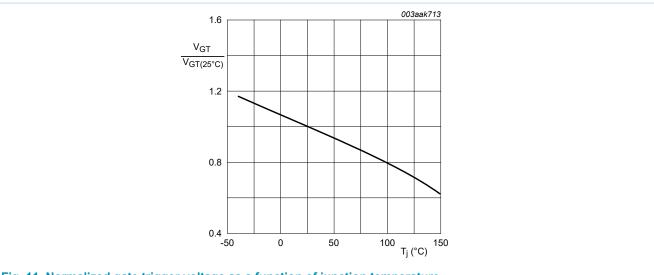
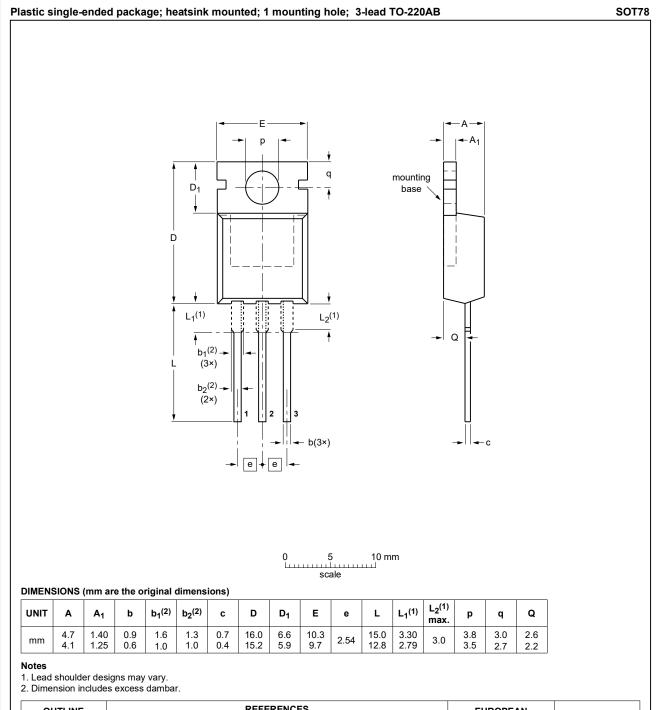


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

## 10. Package outline



| OUTLINE |     | REFER           | ENCES | EUROPEAN ISSUE D |                                 |  |
|---------|-----|-----------------|-------|------------------|---------------------------------|--|
| VERSION | IEC | JEDEC           | JEITA | PROJECTION       | ISSUE DATE                      |  |
| SOT78   |     | 3-lead TO-220AB | SC-46 |                  | <del>08-04-23</del><br>08-06-13 |  |
|         |     |                 |       | - 1              |                                 |  |

Fig. 12. Package outline TO-220AB (SOT78)

## 11. Legal information

#### **Data sheet status**

| Document status [1][2]               | Product status [3] | Definition  |
|--------------------------------------|--------------------|---|
| Objective<br>[short] data<br>sheet   | Development        | This document contains data from the objective specification for product development. |
| Preliminary<br>[short] data<br>sheet | Qualification      | This document contains data from the preliminary specification.                       |
| Product<br>[short] data<br>sheet     | Production         | This document contains the product specification.                                     |

- Please consult the most recently issued document before initiating or completing a design.
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For more information, please visit: http://www.ween-semi.com
For sales office addresses, please send an email to: salesaddresses@ween-semi.com
Date of release: 12 September 2018

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